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- (71) Applicant (for all designated States except US): NAN-OCLUSTER DEVICES LIMITED [NZ/NZ]; Forestry School Building, Forestry Road, Elam, Christchurch, 8004 (NZ).
- (72) Inventors; and
- (75) Inventors/Applicants (for US only): BROWN, Simon, Anthony [NZ/NZ]; 81 Hinau Street, Riccarton,

Christchurch, 8004 (NZ). PARTRIDGE, James, Gordon [GB/NZ]; Unit 5, 477 Madras Street, St Albans, Christchurch, 8001 (NZ).

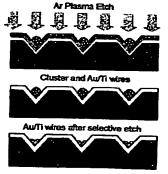
- (74) Agents: ADAMS, Matthew, D et al.; A J Park, 6th Floor Huddart Parker Building, PO Box 949, Wellington, 6015
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# (54) Title: ETCH MASKS BASED ON TEMPLATE-ASSEMBLED NANOCLUSTERS

# (54) Title: ETCH MASKS BASED ON TEMPLATE-ASSEMBLED NANOCLUSTERS Thermally Oxidised SI All Plasma Etch Anisotropic Si etching Metallised and Oxidised SI Cluster and Au/Ti wires Cluster and Au/Ti wires Au/Ti wires after selective etch atomic clusters (e.g. antimony or bismuth) into V-grooves. These structures, preferably in the form of nanowires, are used as etching masks for the subsequent etching of the substrate. In an embodiment the V-grooves are metallised (e.g. with titamium or solid) migr





atomic clusters (e.g. antimony or bismuth) into V-grooves. These structures, preferably in the form of nanowires, are used as etching masks for the subsequent etching of the substrate. In an embodiment the V-grooves are metallised (e.g. with titanium or gold) prior to the deposition of the clusters. In this case the use of the nanostructures (e.g. antimony or bismuth) as an etching mask results in the formation of nanostructures of the underlying metal (e.g. titanium or gold). In this way the dimensions of the nanowires are transferred into the underlying metal film and the method allows fabrication of nanowires from materials (e.g. titanium or gold) that cannot be deposited as clusters.